

10400 Eaton Place
Suite 312
FAIRFAX, VA
Phone: (703) 385-5200
Fax: (703) 385-5080

KEATING & BENNETT LLP

Fax

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JUL 29 2003

TECHNOLOGY CENTER 2800

To: Examiner K. Addison

From: Christopher A. Bennett

Fax: 703-872-9318

Date: July 29, 2003

Phone: 703-306-5855

Pages: 11

Re: 09/840,359

CC:

36856.472

•Comments:

Examiner Addison,

Please find attached the following documents for the above-identified application:

- A Request for Reconsideration;
- A three-month Petition for Extension of Time; and
- A Credit Card Form in the amount of \$930.00;

Respectfully submitted,



Christopher A. Bennett

for

KEATING & BENNETT, LLP
(Registration Number 46,710)

CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this correspondence is being transmitted to
Group Art Unit 2834, 703-872-9318, addressed to:
Commissioner for Patents, P.O. Box 1450, Alexandria, VA
22313-1450.

Date: July 29, 2003

Sonia V. McVeen
Sonia V. McVeen

PATENT
36856.472

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Hajime KANDOU et al.

Serial No.: 09/840,359

Filed: April 23, 2001

Title: SURFACE ACOUSTIC WAVE DEVICE

Art Unit: 2834

Examiner: K. Addison

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REQUEST FOR RECONSIDERATION

TECHNOLOGY CENTER 2800

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

In response to the Office Action dated January 29, 2003, the period for response to which has been extended to July 29, 2003, by the accompanying Petition for Three-Month Extension of Time, please reconsider the above-identified application in view of the following remarks.

Claims 1 and 3-14 are pending in this application.

Claims 1 and 3-14 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Kadota et al. (U.S. 5,432,392) in view of Kadota ("Combination of ZnO Film and Quartz to Realize Large Coupling Factor and Excellent Temperature Coefficient for SAW Devices"). Applicants respectfully traverse this rejection.

Claim 1 recites:

"A surface acoustic wave device, comprising:
a quartz substrate;
a piezoelectric thin film disposed on said quartz substrate;
**comb electrodes disposed between said quartz substrate and
said piezoelectric thin film; and**
**the normalized film thickness H/λ of said piezoelectric thin film
is at least about 0.20, wherein the film thickness of said piezoelectric
thin film is H , and the wavelength of a surface acoustic wave is λ ."**